

Search Notes

Application/Control No.

10/750,599

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

KIM, JAE-WAN

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	551-559	6/18/2005	HLN
327	175,311		
327	531,532		
333	172		
340	825.71		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with DinhLE, Primary Examiner, AU # 2816	6/16/2005	HLN
EAST Text Search	6/18/2005	HLN
Shepardize Search	6/20/2005	HLN